# **EPC2052 – Enhancement Mode Power Transistor**

 $V_{DS}$ , 100 V  $R_{DS(on)}$  , 13.5 m $\Omega$ I<sub>D</sub>, 8.2 A







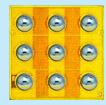


Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)'}$  while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$ and zero Q<sub>RR</sub>. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

	Maximum Ratings				
	PARAMETER VALUE UNIT				
\ \ \	Drain-to-Source Voltage (Continuous)	100	<b>V</b>		
V <sub>DS</sub>	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120			
I <sub>D</sub>	Continuous (T <sub>A</sub> = 25°C)	8.2	Δ.		
	Pulsed (25°C, $T_{PULSE} = 300 \mu s$ )	74	Α		
V <sub>GS</sub>	Gate-to-Source Voltage	6	V		
	Gate-to-Source Voltage	-4			
TJ	Operating Temperature	-40 to 150	-  °C		
T <sub>STG</sub>	Storage Temperature	-40 to 150			

	Thermal Characteristics				
	PARAMETER	ТҮР	UNIT		
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2			
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	15	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	74			

Note 1: Raia is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote\_Thermal\_Performance\_of\_eGaN\_FETs.pdf for details.



EPC2052 eGaN® FETs are supplied in passivated die form with solder bumps. Die size: 1.5 mm x 1.5 mm

#### **Applications**

- 48 V Servers
- · Lidar/Pulsed Power
- · Isolated Power Supplies
- Point of Load Converters
- · Class D Audio
- LED Lighting
- Low Inductance Motor Drive

#### **Benefits**

- Higher Switching Frequency Lower switching losses and lower drive power
- Higher Efficiency Lower conduction and switching losses, zero reverse recovery losses
- Ultra Small Footprint Higher power density

	Static Characteristics ( $T_J = 25^{\circ}$ C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
BV <sub>DSS</sub>	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, } I_D = 0.2 \text{ mA}$	100			V	
I <sub>DSS</sub>	Drain-Source Leakage	$V_{DS} = 80 \text{ V}, \ V_{GS} = 0 \text{ V}, T_J = 25^{\circ}\text{C}$		0.02	0.15	mA	
	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}, T_J = 25^{\circ}\text{C}$		0.01	1.8	mA	
I <sub>GSS</sub>		V <sub>GS</sub> = 5 V, T <sub>J</sub> = 125°C		0.2	4	mA	
	Gate-to-Source Reverse Leakage#	V <sub>GS</sub> = -4 V, T <sub>J</sub> = 25°C		0.01	0.18	mA	
V <sub>GS(TH)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 3 \text{ mA}$	0.8	1.4	2.5	V	
R <sub>DS(on)</sub>	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 11 \text{ A}$		10	13.5	mΩ	
$V_{SD}$	Source-Drain Forward Voltage#	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		2.0		V	

<sup>#</sup> Defined by design. Not subject to production test.

	Dynamic Characteristics $(T_j = 25^{\circ}C)$ unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance			441	584	
$C_{RSS}$	Reverse Transfer Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}$		3.2		
Coss	Output Capacitance			195	293	pF
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)			227		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)	$V_{DS} = 0 \text{ to } 50 \text{ V}, V_{GS} = 0 \text{ V}$		274		
$R_{G}$	Gate Resistance			0.7		Ω
Q <sub>G</sub>	Total Gate Charge	$V_{DS} = 50 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 11 \text{ A}$		3.5	4.5	
Q <sub>GS</sub>	Gate to Source Charge			1.5		
$Q_{GD}$	Gate to Drain Charge	$V_{DS} = 50 \text{ V}, I_D = 11 \text{ A}$		0.5		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			1.0		nC
Qoss	Output Charge	$V_{GS} = 0 \text{ V}, V_{DS} = 50 \text{ V}$		13	20	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

<sup>#</sup> Defined by design. Not subject to production test.

Figure 1: Typical Output Characteristics at 25°C

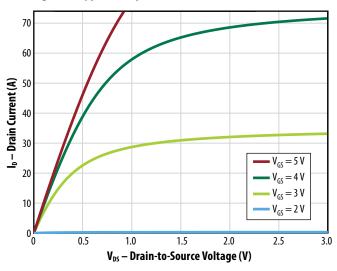


Figure 2: Typical Transfer Characteristics

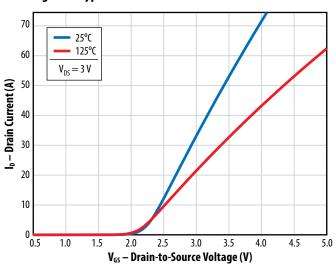


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Currents

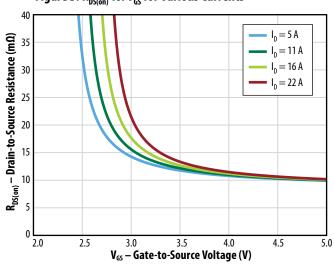
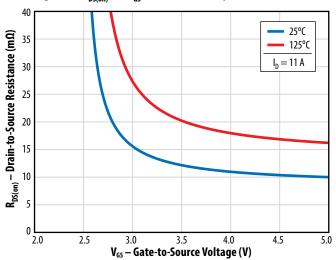


Figure 4:  $\mathbf{R}_{\mathrm{DS(on)}}$  vs.  $\mathbf{V}_{\mathrm{GS}}$  for Various Temperatures



All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>.

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>.



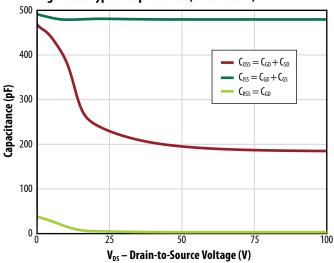


Figure 5b: Typical Capacitance (Log Scale)

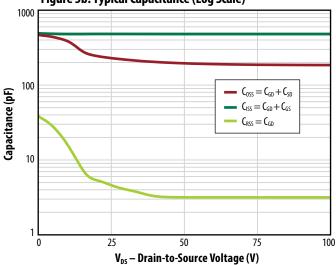


Figure 6: Typical Output Charge and Coss Stored Energy

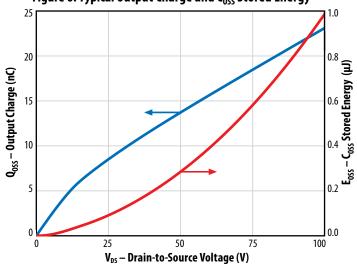
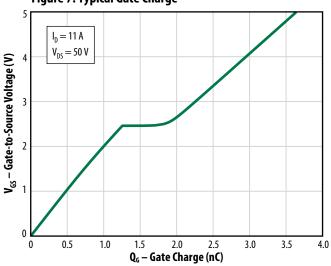


Figure 7: Typical Gate Charge



**Figure 8: Reverse Drain-Source Characteristics** 

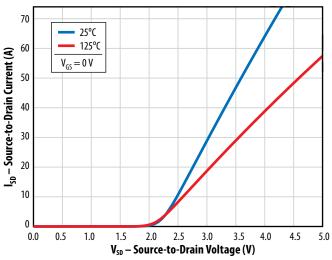
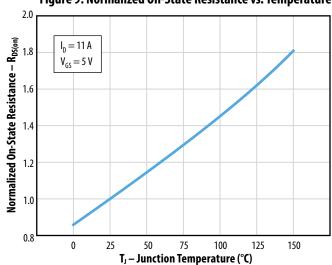


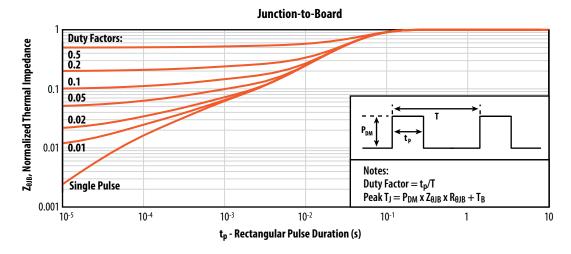
Figure 9: Normalized On-State Resistance vs. Temperature



Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF

Figure 10: Normalized Threshold Voltage vs. Temperature 1.4  $I_D = 3 \text{ mA}$ 1.3 1.2 **Normalized Threshold Voltage** 1.1 1.0 0.9 0.8 0.7 0.6 0 25 50 75 100 125 150 T<sub>J</sub> – Junction Temperature (°C)

**Figure 11: Transient Thermal Response Curves** 



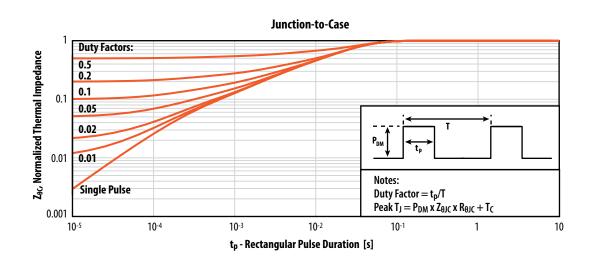
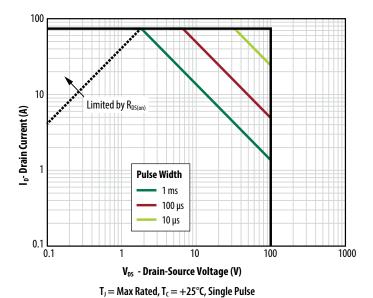
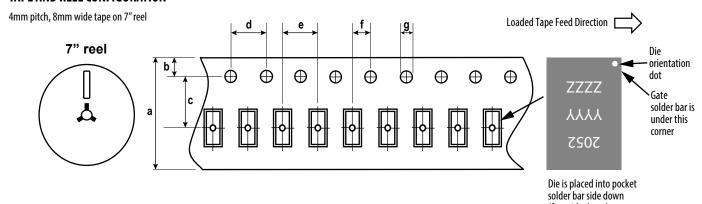


Figure 12: Safe Operating Area



### TAPE AND REEL CONFIGURATION

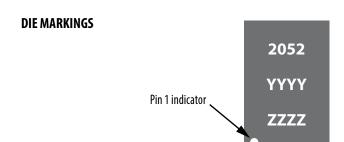


EPC2052 (note 1)		
target	min	max
8.00	7.90	8.30
1.75	1.65	1.85
3.50	3.45	3.55
4.00	3.90	4.10
4.00	3.90	4.10
2.00	1.95	2.05
1.5	1.5	1.6
	8.00 1.75 3.50 4.00 4.00 2.00	target         min           8.00         7.90           1.75         1.65           3.50         3.45           4.00         3.90           4.00         1.95

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

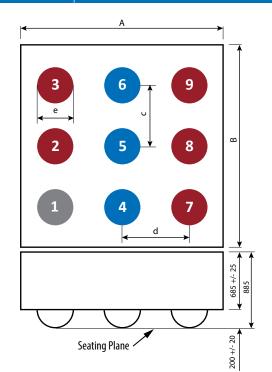
(face side down)



Part		Laser Markings	
Number	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
EPC2052	2052	YYYY	ZZZZ

#### **DIE OUTLINE**

Solder Bump View



DIM	MICROMETERS			
DIM	MIN	Nominal	MAX	
A	1470	1500	1530	
В	1470	1500	1530	
C		450		
d		500		
е	238	264	290	

Pad 1 is Gate;

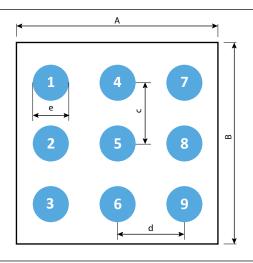
Pads 2, 3, 7, 8, 9 are Source;

Pads 4, 5, 6 are Drain.

Side View

## **RECOMMENDED LAND PATTERN**

(units in  $\mu$ m)



DIM	MICROMETERS
A	1500
В	1500
C	450
d	500
e	230

Pad 1 is Gate:

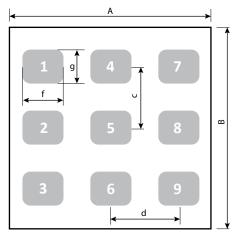
Pads 2, 3, 7, 8, 9 are Source;

Pads 4, 5, 6 are Drain.

## **RECOMMENDED** STENCIL DRAWING

(measurements in µm)

Additional assembly resources available at https://epc-co.com/epc/ DesignSupport/AssemblyBasics.aspx



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DIM	MICROMETERS
A	1500
В	1500
C	450
d	500
f	300
g	250

Pad 1 is Gate;

Pads 2, 3, 7, 8, 9 are Source;

Pads 4, 5, 6 are Drain.

Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, opening per drawing. The corner has a radius of R60. Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

> Information subject to change without notice. Revised September, 2022